

Improving Organizational Performance Through Goal Deployment

Andy Hunt and Jim Oerth

Skyworks Solutions, Inc
20 Sylvan Road, Woburn, MA, 01801, USA
Tel: (781) 376-3220, Email: andy.hunt@skyworksinc.com

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Abstract

Exceptional performance of a manufacturing facility doesn't just happen. It requires effective management of all the various factors, constraints and resources. One important aspect of management is setting goals. This paper presents the goal deployment methodology utilized by Skyworks Solutions' GaAs pHEMT wafer fab. Using this method, the Skyworks Woburn fab has achieved significant operational improvements that have increased company profit margin.

INTRODUCTION

The consumer electronics market is very competitive. Companies that can provide the products which consumers desire with high quality, on time, and with the lowest cost enjoy growth and prosperity. After the design teams have developed desirable products, it is the responsibility of the manufacturing groups to deliver these characteristics. This is accomplished through good management practices. The text book definition of a manager is a person who plans, staffs, organizes, motivates, controls, represents and coordinates the factors of production. Each of these responsibilities is critical to achieving success. This paper will discuss goal deployment, a topic that touches on all of these responsibilities. While conceptually very simple, it is very difficult to be highly effective at goal deployment. Goal deployment involves setting organizational goals and then deploying those goals to every person in the organization. Every person, group, and department must have clearly defined goals that feed up to and support the next level higher goals. Ultimately, every person's goals can be traced to supporting the top level goals of the organization. Routinely reviewing the progress is essential. Corrective action must be taken when satisfactory progress is not made.

RESULTS

Using the goal deployment methodology, critical performance metrics were established. After four years of implementation, all critical performance indicators showed significantly improved results. Example metrics and results are shown in Figures 1, 2, 3, and 4.

Figure 1
Line Yield Normalized to 2004

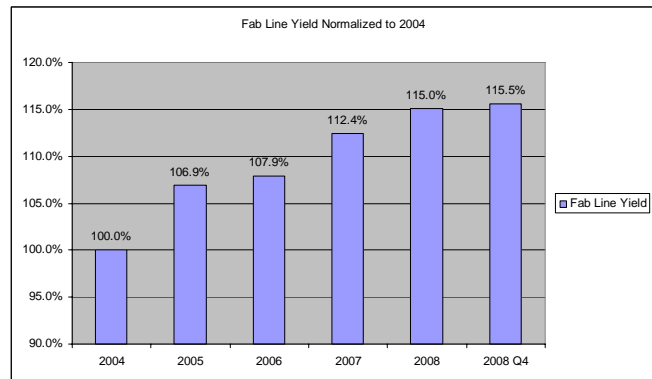


Figure 2
End to End Yield Normalized to 2004

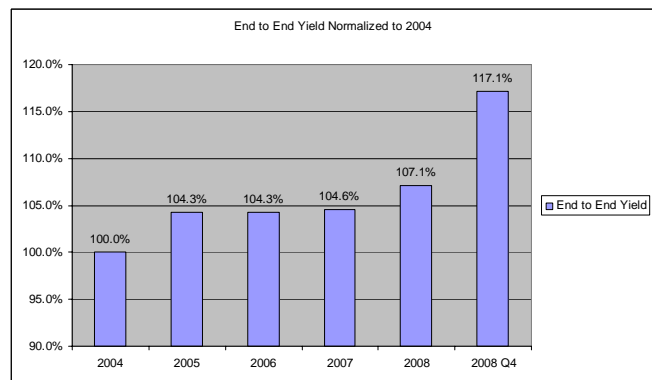


Figure 3
Wafer Output Normalized to 2004

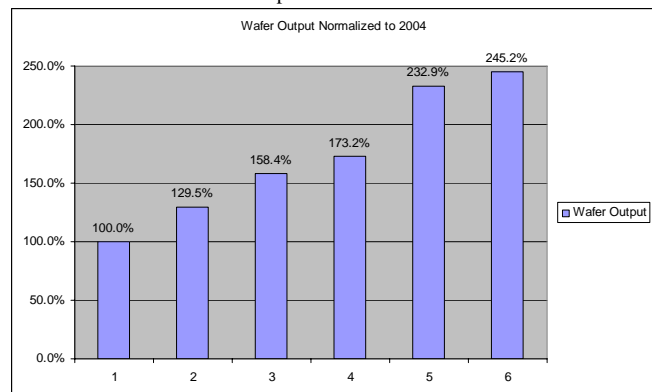
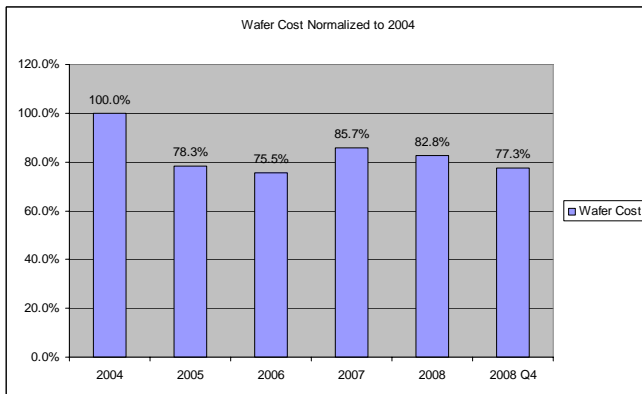


Figure 4
Wafer Cost Normalized to 2004



CONCLUSIONS

Organizational performance is increased by setting SMART goals, deploying them throughout the organization, tracking performance to those goals, and taking corrective action when the plans do not meet the goals. This methodology continues to be used at Skyworks.

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ACRONYMS

SMART: Specific, Measurable, Attainable, Relevant, Time Bound
pHEMT: Pseudomorphic High Electron Mobility Transisto

